

Description

The VST10N038 uses **Super Trench** technology that is uniquely optimized to provide the most efficient high frequency switching performance. Both conduction and switching power losses are minimized due to an extremely low combination of $R_{DS(ON)}$ and Q_g . This device is ideal for high-frequency switching and synchronous rectification.

General Features

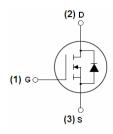
- $V_{DS} = 100V, I_{D} = 130A$ $R_{DS(ON)} < 4.6 \text{m}\Omega @ V_{GS} = 10V$
- Excellent gate charge x R_{DS(on)} product
- Very low on-resistance R_{DS(on)}
- 175 °C operating temperature
- Pb-free lead plating
- 100% UIS tested

Application

- DC/DC Converter
- Ideal for high-frequency switching and synchronous rectification



TO-263



Schematic Diagram

Package Marking and Ordering Information

Device Marking	Device	Device Package	Reel Size	Tape width	Quantity
VST10N038-T3	VST10N038	TO-263	-	-	-

Absolute Maximum Ratings (T_C=25 ℃unless otherwise noted)

Parameter	Symbol	Limit	Unit
Drain-Source Voltage	V _{DS}	100	V
Gate-Source Voltage	Vgs	±20	V
Drain Current-Continuous (Silicon Limited)	I_D	143	А
Drain Current-Continuous (Package Limited)	I _D	135	А
Drain Current-Continuous(T _C =100 °C)	I _D (100℃)	102	Α
Pulsed Drain Current	I _{DM}	500	Α
Maximum Power Dissipation	P _D	210	W
Derating factor		1.4	W/°C
Single pulse avalanche energy (Note 5)	E _{AS}	1050	mJ
Operating Junction and Storage Temperature Range	T_{J},T_{STG}	-55 To 175	$^{\circ}$





Thermal Characteristic

Thermal Resistance, Junction-to-Case (Note 2)	ReJC	0.71	°C/W
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Electrical Characteristics (T_c=25°Cunless otherwise noted)

Parameter	Symbol	Condition	Min	Тур	Max	Unit
Off Characteristics						•
Drain-Source Breakdown Voltage	BV _{DSS}	V _{GS} =0V I _D =250μA	100		-	V
Zero Gate Voltage Drain Current	I _{DSS}	V _{DS} =100V,V _{GS} =0V	-	-	1	μA
Gate-Body Leakage Current	I _{GSS}	V _{GS} =±20V,V _{DS} =0V	-	-	±100	nA
On Characteristics (Note 3)						•
Gate Threshold Voltage	V _{GS(th)}	$V_{DS}=V_{GS}$, $I_{D}=250\mu A$	2.5		4.5	V
Drain-Source On-State Resistance	R _{DS(ON)}	V _{GS} =10V, I _D =60A	-	3.8	4.6	mΩ
Forward Transconductance	g FS	V _{DS} =10V,I _D =60A	-	60	-	S
Dynamic Characteristics (Note4)						•
Input Capacitance	C _{lss}	V _{DS} =50V,V _{GS} =0V,	-	6400	-	PF
Output Capacitance	C _{oss}		-	731	-	PF
Reverse Transfer Capacitance	C _{rss}	F=1.0MHz	-	35	-	PF
Switching Characteristics (Note 4)						•
Turn-on Delay Time	t _{d(on)}	V_{DD} =50V, I_{D} =60A V_{GS} =10V, R_{G} =4.7 Ω	-	19	-	nS
Turn-on Rise Time	t _r		-	76	-	nS
Turn-Off Delay Time	t _{d(off)}		-	48	-	nS
Turn-Off Fall Time	t _f		-	14	-	nS
Total Gate Charge	Qg	V _{DS} =50V,I _D =60A,	-	92		nC
Gate-Source Charge	Q _{gs}		-	35.4		nC
Gate-Drain Charge	Q_{gd}	V _{GS} =10V	-	18.8		nC
Drain-Source Diode Characteristics						•
Diode Forward Voltage (Note 3)	V _{SD}	V _{GS} =0V,I _S =135A	-		1.2	V
Diode Forward Current (Note 2)	Is		-	-	135	А
Reverse Recovery Time	t _{rr}	$T_J = 25$ °C, $I_F = I_S$	-	63		nS
Reverse Recovery Charge	Qrr	$di/dt = 100A/\mu s^{(Note3)}$	-	142		nC

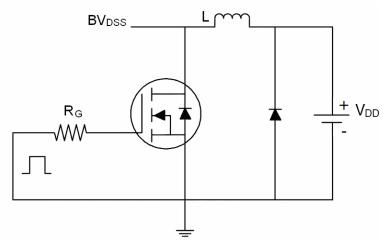
Notes:

- 1. Repetitive Rating: Pulse width limited by maximum junction temperature.
- 2. Surface Mounted on FR4 Board, $t \le 10$ sec.
- 3. Pulse Test: Pulse Width \leq 300 μ s, Duty Cycle \leq 2%.
- 4. Guaranteed by design, not subject to production
- 5. EAS condition : Tj=25 $^{\circ}\text{C}$,VDD=50V,VG=10V,L=0.5mH,Rg=25 Ω

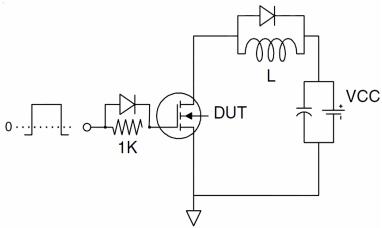


Test Circuit

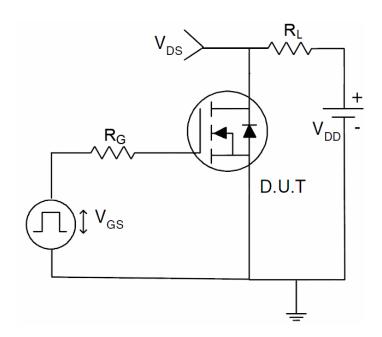
1) E_{AS} test Circuit



2) Gate charge test Circuit



3) Switch Time Test Circuit







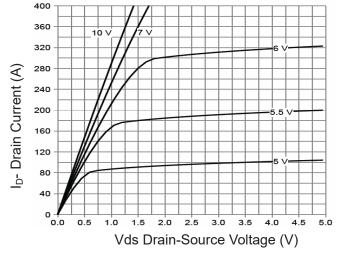


Figure 1 Output Characteristics

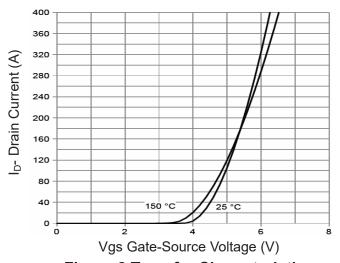


Figure 2 Transfer Characteristics

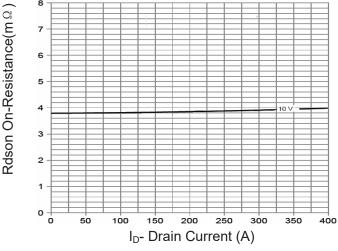


Figure 3 Rdson-Drain Current

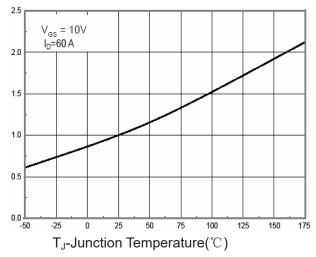


Figure 4 Rdson-JunctionTemperature

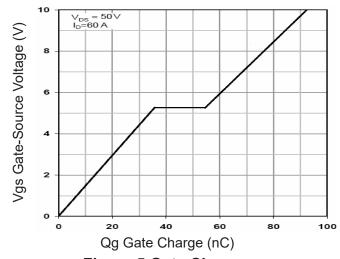


Figure 5 Gate Charge

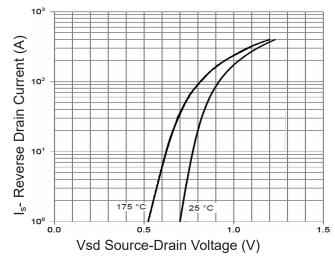


Figure 6 Source- Drain Diode Forward



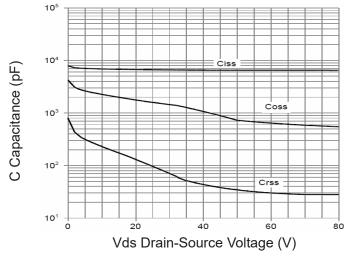


Figure 7 Capacitance vs Vds

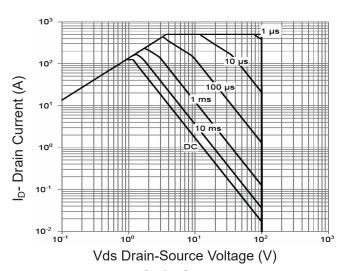


Figure 8 Safe Operation Area

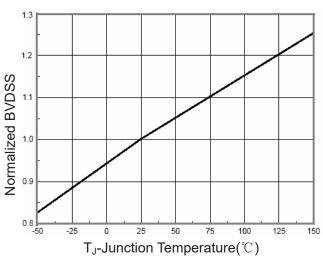


Figure 9 BV_{DSS} vs Junction Temperature

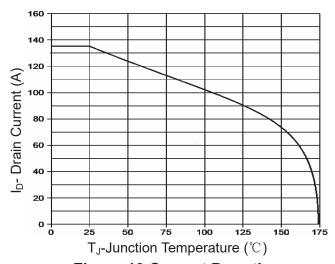


Figure 10 Current De-rating

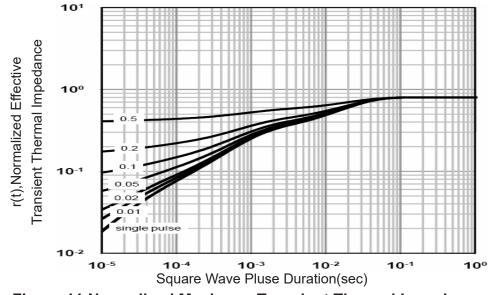


Figure 11 Normalized Maximum Transient Thermal Impedance